

REMARKS

Claim 9 has been amended to delete multiple-dependency and claim 25 has been added accordingly.

Attached hereto is a marked-up version of the changes made to the specification and claims by the current amendment. The attached pages are captioned "**Version with markings to show changes made.**"

Early, favorable prosecution on the merits is respectfully requested.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,



Sean M. McGinn

Registration No.: 34,386

Date: 5/29/01
McGinn & Gibb, PLLC
8321 Old Courthouse Road; Suite 200
Vienna, Virginia 22182-3817
(703) 761-4100
Customer No. 21254

In the claims:

9. (Amended) A semiconductor device tester as claimed in claim 3 [or 4], wherein said comparator means includes means for integrating current flown from a rising edge to a falling edge of a current waveform generated by a certain circuit pattern on the test sample, divider means for dividing a result of integration from said integrating means by a distance between the rising edge and the falling edge of the current waveform and average value comparator means for comparing the quotient obtained by said divider.